
Microelectronics User Group Meeting

TWEPP 2011, Vienna, Austria
27/9/2011



Agenda

- “News on the 130nm Technology”
by Wojciech Bialas (CERN) (10’)
- “Design Toos, Flows and Library Aspects during the FE-I4 Implementation on Silicon”
by Vladimir Zivkovic (NIKHEF Institute) (15’)
- “Noise and Radiation Hardness of 65nm CMOS Transistors and Pixel Front-Ends”
by Massimo Manghisoni (University of Bergamo) (20’)
- Access of 65nm technology through CERN.
by Kostas Kloukinas (CERN) (10’)